유리기판에 저온 증착한 GZOB 박막의 두께에 따른 특성 변화

유현규, 이규일, 이종환, 강현일, 이태용, 김용권, 송준태^{*} 성균관대학교 정보통신공학부

Dependance of thickness on the properties of B doped ZnO:Ga (GZOB) thin film on glass substrate at room temperature

Hyun-Kyu Yu, Kyu-Il Lee, Jong-Hwan Lee, Hyun-Il Kang, Tae-Yong Lee, Eung-Kwon Kim, and Joon-Tae Song School of Information and Communication Engineering, SungKyunKwan University

Abstract: In this study, effect of thickness on structural, electrical and optical properties of B doped ZnO:Ga (GZOB) films was investigated. GZOB films were deposited on glass substrates by DC magnetron sputtering. The thickness range of films were from 100 nm to 600 nm to identified as increasing thickness, stress between substrate and GZOB film. The average transmittance of the films was over 80 % until 500 nm. Then a resistivity of $9.16\times10^{-4}\Omega$ -cm was obtained. We presented that a GZOB film of 400 nm was optimization to obtain a high transmittance and conductivity.

Key Words: GZOB, DC magnetron sputtering, thickness